Application/Control No.	Applicant(s)/Patent under Reexamination	
10/511,549	OHISHI ET AL.	
Examiner	Art Unit	

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Clark D. Petersen

SEARCHED					
Class	Subclass	Date	Examiner		
No	NE PI	ERFORM	1ED		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
STN: SNORF25, GPR119	3/1/2007	CDP		
PUBMED: see attached history	3/1/2007	CDP		
EAST: JPO, EPO, DERWENT, USPATFULL, USPGPUBS, OCR	3/1/2007	CDP		
Inventor name search: EAST, PALM	3/1/2007	CDP		
STIC sequence search: SEQ ID 2 and 4	7/1/2006			